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Characterization of waste – Screening methods for elemental composition by X-ray fluorescence spectrometry for on-site verification

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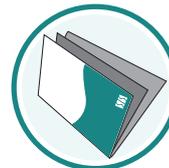
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TECHNICAL REPORT

CEN/TR 16176

RAPPORT TECHNIQUE

TECHNISCHER BERICHT

November 2011

ICS 13.030.01

English Version

Characterization of waste - Screening methods for elemental composition by X-ray fluorescence spectrometry for on-site verification

Caractérisation des déchets - Méthodes de dépistage pour la détermination de la composition élémentaire par spectrométrie à fluorescence de rayons X pour les vérifications in situ

Charakterisierung von Abfällen - Anwendung von Screening-Verfahren bei der Vor-Ort-Prüfung - Bestimmung der elementaren Zusammensetzung mittels Röntgenfluoreszenzspektrometrie

This Technical Report was approved by CEN on 3 October 2011. It has been drawn up by the Technical Committee CEN/TC 292.

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Contents		Page
Foreword.....		3
Introduction		4
1 Purpose.....		5
2 Description of the XRF technique		5
2.1 General.....		5
2.2 Principle of XRF		5
2.3 Interferences		6
2.4 Measurement.....		7
2.5 Calibration/evaluation		7
2.6 Validation.....		8
3 Overview XRF applications.....		9
4 Influence of the sample preparation on the result		9
5 Evaluation of the XRF screening technique		13
6 Robustness study: description and results.....		15
6.1 General.....		15
6.2 Technical description of the instruments		15
6.3 Description of the selected samples and their characterisation		16
6.4 Results of the field trial		17
6.4.1 Defining performance criteria.....		17
6.4.2 Evaluation of the repeatability, reproducibility and accuracy		18
6.4.3 Influence of the sample pretreatment.....		19
6.4.4 Evaluation of false positive / false negative results.....		22
6.4.5 Limit of detection		22
6.4.6 General evaluation of the portable XRF instruments.....		22
6.4.7 Conclusions of the robustness study		22
7 Conclusions		23
Annex A (informative) Pre-normative robustness study.....		24
Annex B (informative) Summary of EPA report on XRF technologies for measuring trace elements in soil and sediment		38
Bibliography.....		42

Foreword

This document (CEN/TR 16176:2011) has been prepared by Technical Committee CEN/TC 292 "Characterization of Waste", the secretariat of which is held by NEN.

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Introduction

Although bench-top instruments generally provide much more conclusive results, hand-held XRF instruments are becoming an interesting screening tool for a wide range of applications. Their portability and their ability to identify, characterise and also analyse a wide range of elements rapidly, along with the fact that little technical expertise is needed to operate them, make the hand-held XRF instruments very useful. The recent developments in the XRF technology tends to create hand-held instruments with performance levels approaching bench top equipment. Some years ago, hand-held instruments required the use of radioactive materials to provide a source of X-rays, resulting in very stringent regulatory demands. The development of miniaturised low-power X-ray tubes overcomes these problems and provides new opportunities for the hand-held instruments. Recent advances in the improvement of the detector efficiency led to a significant decrease in the detection limits for hand-held systems compared to the older ones. Due to the required compact configuration for hand-held XRF systems only energy dispersive X-ray fluorescence (EDXRF) are on the market. On the other hand wavelength dispersive XRFs (WDXRF) are generally more laborious.

The use of the XRF technique in field screening trials can provide a number of benefits compared to the traditional laboratory techniques. On-site analyses ensure a fast turnaround between the measurement itself and the availability of data results. Sample preparation is frequently unnecessary or will be limited. Screening can gain a large sample data set on a short time frame, but that can be at the expense of the accuracy and precision. When better accuracy is required confirmative analysis has to be performed. This approach will surely result in a significant reduction of analysis time and costs.

This report focuses on hand-held XRF instruments, although portable bench-top instruments are also on the market for this type of application. Whenever portable instruments are specifically addressed in this report, both types of instruments can be considered.

1 Purpose

In the framework of the EU Directive 99/31/EC on the landfill of waste and the EU Directive 2000/76/EC on the incineration of waste there is a growing need for fast, easy-to-handle screening tools. In this respect, low costs, fast analyses, control of truck loads and yes/no-acceptance decisions are relevant criteria. The X-ray fluorescence (XRF) technique meets these requirements as a screening tool for on-site verification on the landfill and for entrance control on the incineration plants.

Recent developments of the XRF technology have made this technique a method of choice for on-site analysis, namely miniaturisation of the XRF system (X-ray tube), the optimisation of the calibration programmes and the improvement of the detectors. Therefore, a state-of-the-art document on the current progress of the XRF technology and instruments available for on-site analysis shall support the key arguments, dealing with the pro's and contra's, and the performance of these systems to be expected.

The XRF standard EN 15309, is validated for Na, Mg, Al, Si, P, S, Cl, K, Ca, Ti, V, Cr, Mn, Fe, Co, Ni, Cu, Zn, As, Se, Br, Rb, Sr, Y, Zr, Nb, Mo, Ag, Cd, Sn, Sb, Te, I, Cs, Ba, Ta, W, Hg, Tl, Pb, Bi, Th and U, and describes in the informative annex the procedures for hand-held XRF systems together with the portable/transportable systems (placed in mobile labs). Although XRF can analyse a broad range of elements, the main focus of this document is on the series of elements that is also being covered by EN 15309. Of that series the following elements are related to the landfill directive: As, Ba, Cd, Cr, Cu, Hg, Mo, Ni, Pb, Sb, Se, Zn.

The information in this document will be useful in all cases in which on-site determination of the elemental compositions of waste is needed and hand-held instrumentation is therefore used. These cases may include, beside landfills and incineration plant, also waste treatment plants, contaminations soil sites and controls of transports of waste.

2 Description of the XRF technique

2.1 General

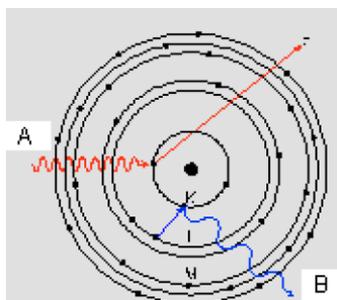
X-ray fluorescence spectrometry is a fast and reliable method for the analysis of the total content of certain elements within different matrices. The quality of the results obtained depends very closely on the type of instrument used, e.g. hand-held, bench top. When selecting a specific instrument several factors have to be considered, such as the matrices to be analysed, elements to be determined, detection limits required and the measuring time. The quality of the results depends on the element to be determined and on the surrounding matrix, together with the applied sample preparation method, and the heterogeneity of the test sample.

2.2 Principle of XRF

An electron can be ejected from its atomic orbital by the absorption of a light wave (photon) of sufficient energy [1]. The energy of the photon ($h\nu$) must be greater than the energy with which the electron is bound to the nucleus of the atom. When an inner orbital electron is ejected from an atom, an electron from a higher energy level orbital will be transferred to the lower energy level orbital. During this transition a photon maybe emitted from the atom. This fluorescent light is called the characteristic X-ray of the element (Figure 1). The energy of the emitted photon will be equal to the difference in energies between the two orbitals occupied by the electron making the transition. Because the energy difference between two specific orbital shells, in a given element, is always the same (i.e. characteristic of a particular element), the photon emitted when an electron moves between these two levels, will always have the same energy. Therefore, by determining the energy (wavelength) of the X-rays (photon) emitted by a particular element, it is possible to determine the identity of that element.

For a particular energy (wavelength) of fluorescent light emitted by an element, the number of photons per unit time (generally referred to as peak intensity or count rate) is related to the amount of that analyte in the sample. The counting rates for all detectable elements within a sample are usually calculated by counting, for a set amount of time, the number of photons that are detected for the various analytes' characteristic X-ray energy lines. It is important to note that these fluorescent lines are actually observed as peaks with a semi-Gaussian distribution depending on the resolution of modern detector technology. Therefore, by

determining the energy of the X-ray peaks in a sample's spectrum, and by calculating the count rate of the various elemental peaks, it is possible to qualitatively establish the elemental composition of the samples and to quantitatively measure the concentration of these elements.

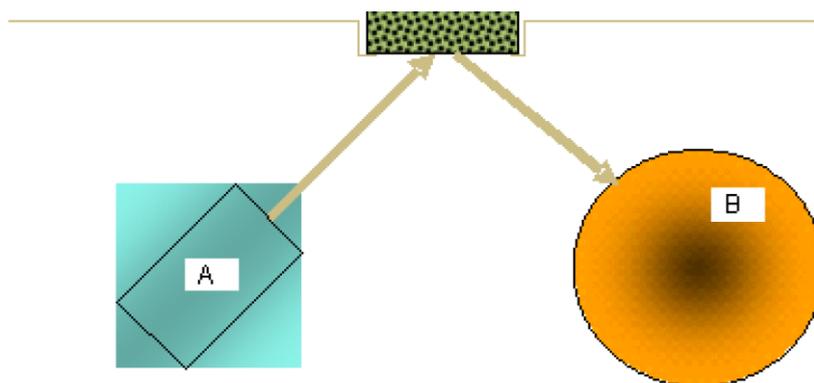


Key

- A excitation: X-rays from X-ray source
- B fluorescence: Characteristic X-ray

Figure 1 — Principle of XRF

The basic configuration of an EDXRF system consists of an excitation source and a detector, coupled to data processing unit, as shown in Figure 2.



Key

- A X-ray source
- B detector

Figure 2 — Basic configuration of an XRF system

2.3 Interferences

Interferences in X-ray fluorescence spectrometry are due to spectral line overlaps, matrix effects, spectral artefacts and particle size or mineralogical effects.

Spectral line overlaps occur when an analytical line cannot be resolved from the line of a different element. Corrections for these interferences are made using the algorithms provided with the software.

Matrix effects occur when the X-ray fluorescence radiation from the analyte element is absorbed or enhanced by other elements in the sample before it reaches the detector. In the case of complex matrices these effects generally have to be corrected.

Spectral artefacts e.g. escape peaks, sum peaks, pulse pile up lines, dead time, Bremsstrahlung correction, are accounted for by the provided software. Spectral artefacts differ for energy dispersive and wavelength dispersive XRF spectrometry.

Particle size effects can be reduced by milling the sample, and both particle size and mineralogical effects can be eliminated by preparing bead samples. It is vital for quantitative analysis that the same sample preparation procedure is applied to both the standards and the samples to be analysed.

2.4 Measurement

All X-ray spectrometers are supplied with a spectrometer software programme to operate the instrument. The software packages are manufacturer depended and contain two major modules:

- analytical measurement programme for data collection. This module controls the measurement of a sample using a certain set of measurement parameters e.g. tube setting (kV, mA), targets and crystals, detectors, measurement times. The analytical programme is always linked to a selected evaluation and calibration programme. Actually, the same measurement conditions have to be applied for both the standards of the calibration curve and the samples. Because in screening analysis the measurements will be performed with the predefined analytical programmes, no further detailed descriptions will be given of the analytical measurement parameters. Follow the manufacturer's instruction for further operation and handling of the analytical software package;
- evaluation programme for data processing. This module converts the measured intensities of the different element lines to elemental concentrations taking all corrections into account. There are various types of evaluation programmes available and each manufacturer has set up his own programmes for data processing based on the XRF principles.

Sensitivity, instrumental detection limits and precision are instrument dependent and should therefore be investigated and established for each individual analyte line on that particular instrument, and, if relevant, as a function of matrix type and sample preparation procedure.

The XRF systems (hand-held as well as bench top) for screening purposes are all provided with precalibrated measurement programmes, setup by the manufacturer, and therefore the user does not need to calibrate the system itself. The user may be able to calibrate the XRF system itself, but it is not a requirement. It should be stressed out that the user needs to verify the calibration programme using reference samples in order to gain insights in the expected accuracy and precision of the XRF calibration programme. More information about the validation will be described in 2.6.

2.5 Calibration/evaluation

For calibration purposes the measurement of analyte lines of samples of known composition is needed. The basic equation implies a linear relationship between the intensity and the concentration.

$$c_i = a_{i,0} + a_{i,1} \times I_i \quad (1)$$

where

c_i is the concentration of the element of interest, expressed as mg/kg or percentage dry matter;

$a_{i,0}$ is the offset of the calibration curve;

$a_{i,1}$ is the slope of the calibration curve;

I_j is the net intensity of the element of interest, expressed as counts per second.

Matrix effects have to be taken into account in X-ray spectrometry according to the following equation: